

METHOD OF DEFECT CONTROL

Appl. No. : 10/708,783 Confirmation No. 2782
Applicant : Long-Hui Lin
Filed : March 25, 2004
TC/A.U. : 2863
Examiner : Xiuqin Sun
Docket No. : LKSP0026USA0
Customer : 27765
No. :

Commissioner for Patents
P.O. Box 1450
Alexandria VA 22313-1450

AMENDMENT

Sir:

- 5 In response to the Office action of April 18, 2005, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 4 of this paper.